Microchip Technology - A54SX32A-PQG208A Datasheet

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	2880
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	174
Number of Gates	48000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 125°C (TA)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx32a-pqg208a

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Logic Module Design

The SX-A family architecture is described as a "sea-of-modules" architecture because the entire floor of the device is covered with a grid of logic modules with virtually no chip area lost to interconnect elements or routing. The Actel SX-A family provides two types of logic modules: the register cell (R-cell) and the combinatorial cell (C-cell).

The R-cell contains a flip-flop featuring asynchronous clear, asynchronous preset, and clock enable, using the S0 and S1 lines control signals (Figure 1-2). The R-cell registers feature programmable clock polarity selectable on a register-by-register basis. This provides additional flexibility while allowing mapping of synthesized functions into the SX-A FPGA. The clock source for the R-cell can be chosen from either the hardwired clock, the routed clocks, or internal logic.

The C-cell implements a range of combinatorial functions of up to five inputs (Figure 1-3). Inclusion of the DB input and its associated inverter function allows up to 4,000 different combinatorial functions to be implemented in a single module. An example of the flexibility enabled by the inversion capability is the ability to integrate a 3-input exclusive-OR function into a single C-cell. This facilitates construction of 9-bit parity-tree functions with 1.9 ns propagation delays.

Module Organization

All C-cell and R-cell logic modules are arranged into horizontal banks called Clusters. There are two types of Clusters: Type 1 contains two C-cells and one R-cell, while Type 2 contains one C-cell and two R-cells.

Clusters are grouped together into SuperClusters (Figure 1-4 on page 1-3). SuperCluster 1 is a two-wide grouping of Type 1 Clusters. SuperCluster 2 is a two-wide group containing one Type 1 Cluster and one Type 2 Cluster. SX-A devices feature more SuperCluster 1 modules than SuperCluster 2 modules because designers typically require significantly more combinatorial logic than flip-flops.

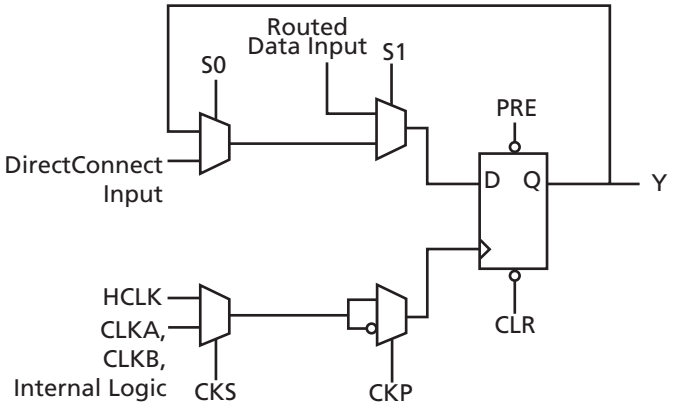


Figure 1-2 • **R-Cell**

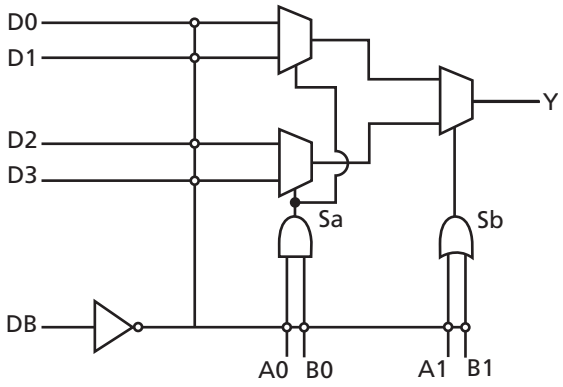


Figure 1-3 • **C-Cell**

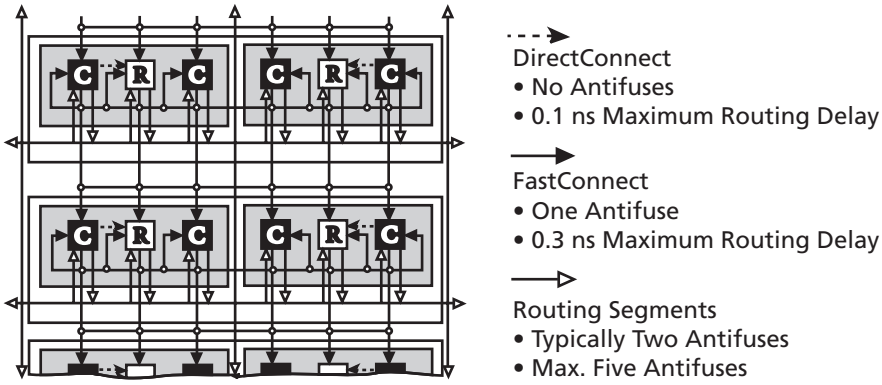


Figure 1-5 • **DirectConnect and FastConnect for Type 1 SuperClusters**

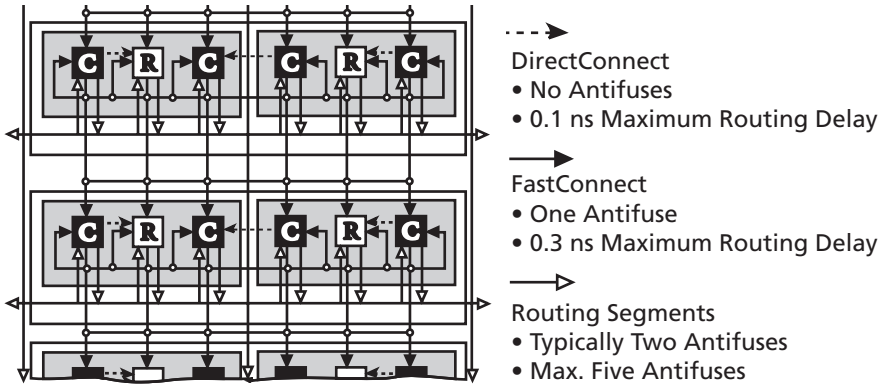


Figure 1-6 • **DirectConnect and FastConnect for Type 2 SuperClusters**

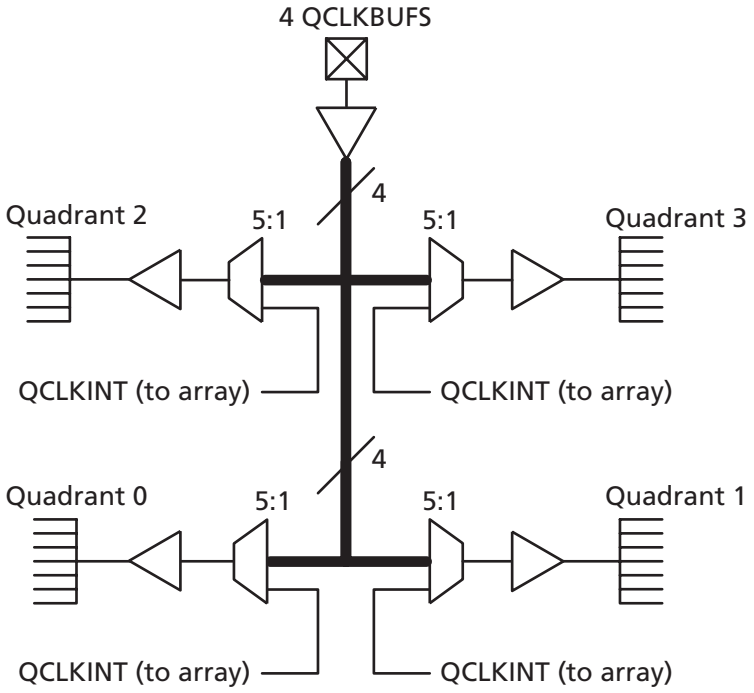


Figure 1-9 • **SX-A QCLK Architecture**

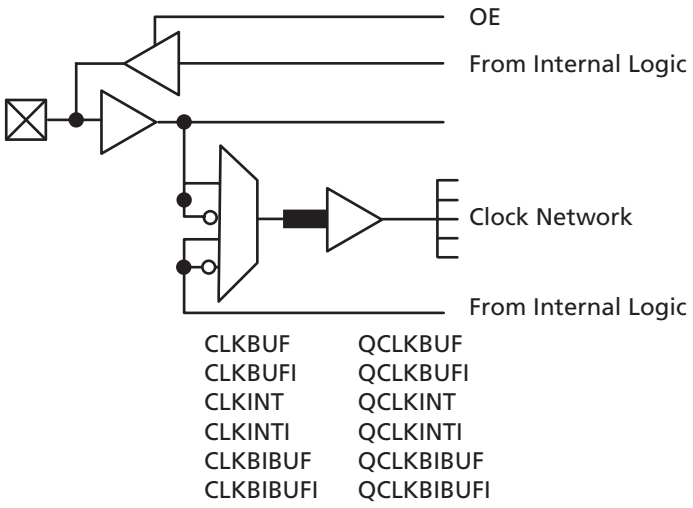


Figure 1-10 • **A54SX72A Routed Clock and QCLK Buffer**

Probing Capabilities

SX-A devices also provide an internal probing capability that is accessed with the JTAG pins. The Silicon Explorer II diagnostic hardware is used to control the TDI, TCK, TMS, and TDO pins to select the desired nets for debugging. The user assigns the selected internal nets in Actel Silicon Explorer II software to the PRA/PRB output pins for observation. Silicon Explorer II automatically places the device into JTAG mode. However, probing functionality is only activated when the TRST pin is driven high or left floating, allowing the internal pull-up resistor to pull TRST High. If the TRST pin is held Low, the TAP controller remains in the Test-Logic-Reset state so no probing can be performed. However, the user must drive the TRST pin High or allow the internal pull-up resistor to pull TRST High.

When selecting the **Reserve Probe Pin** box as shown in Figure 1-12 on page 1-9, direct the layout tool to reserve the PRA and PRB pins as dedicated outputs for probing. This **Reserve** option is merely a guideline. If the designer assigns user I/Os to the PRA and PRB pins and selects the **Reserve Probe Pin** option, Designer Layout will override the **Reserve Probe Pin** option and place the user I/Os on those pins.

To allow probing capabilities, the security fuse must not be programmed. Programming the security fuse disables the JTAG and probe circuitry. Table 1-9 summarizes the possible device configurations for probing once the device leaves the Test-Logic-Reset JTAG state.

Table 1-9 • **Device Configuration Options for Probe Capability (TRST Pin Reserved)**

JTAG Mode	TRST[1]	Security Fuse Programmed	PRA, PRB[2]	TDI, TCK, TDO[2]
Dedicated	Low	No	User I/O[3]	JTAG Disabled
	High	No	Probe Circuit Outputs	JTAG I/O
Flexible	Low	No	User I/O[3]	User I/O[3]
	High	No	Probe Circuit Outputs	JTAG I/O
		Yes	Probe Circuit Secured	Probe Circuit Secured

Notes:

1. *If the TRST pin is not reserved, the device behaves according to TRST = High as described in the table.*
2. *Avoid using the TDI, TCK, TDO, PRA, and PRB pins as input or bidirectional ports. Since these pins are active during probing, input signals will not pass through these pins and may cause contention.*
3. *If no user signal is assigned to these pins, they will behave as unused I/Os in this mode. Unused pins are automatically tristated by the Designer software.*

Pin Description

CLKA/B, I/O **Clock A and B**

These pins are clock inputs for clock distribution networks. Input levels are compatible with standard TTL, LVTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. The clock input is buffered prior to clocking the R-cells. When not used, this pin must be tied Low or High (NOT left floating) on the board to avoid unwanted power consumption.

For A54SX72A, these pins can also be configured as user I/Os. When employed as user I/Os, these pins offer built-in programmable pull-up or pull-down resistors active during power-up only. When not used, these pins must be tied Low or High (NOT left floating).

QCLKA/B/C/D, I/O **Quadrant Clock A, B, C, and D**

These four pins are the quadrant clock inputs and are only used for A54SX72A with A, B, C, and D corresponding to bottom-left, bottom-right, top-left, and top-right quadrants, respectively. They are clock inputs for clock distribution networks. Input levels are compatible with standard TTL, LVTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. Each of these clock inputs can drive up to a quarter of the chip, or they can be grouped together to drive multiple quadrants. The clock input is buffered prior to clocking the R-cells. When not used, these pins must be tied Low or High on the board (NOT left floating).

These pins can also be configured as user I/Os. When employed as user I/Os, these pins offer built-in programmable pull-up or pull-down resistors active during power-up only.

GND **Ground**

Low supply voltage.

HCLK **Dedicated (Hardwired) Array Clock**

This pin is the clock input for sequential modules. Input levels are compatible with standard TTL, LVTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. This input is directly wired to each R-cell and offers clock speeds independent of the number of R-cells being driven. When not used, HCLK must be tied Low or High on the board (NOT left floating). When used, this pin should be held Low or High during power-up to avoid unwanted static power consumption.

I/O **Input/Output**

The I/O pin functions as an input, output, tristate, or bidirectional buffer. Based on certain configurations, input and output levels are compatible with standard TTL, LVTTL, LVCMOS2, 3.3 V PCI or 5 V PCI specifications. Unused I/O pins are automatically tristated by the Designer software.

NC **No Connection**

This pin is not connected to circuitry within the device and can be driven to any voltage or be left floating with no effect on the operation of the device.

PRA/B, I/O **Probe A/B**

The Probe pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the other probe pin to allow real-time diagnostic output of any signal path within the device. The Probe pin can be used as a user-defined I/O when verification has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality.

TCK, I/O **Test Clock**

Test clock input for diagnostic probe and device programming. In Flexible mode, TCK becomes active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TDI, I/O **Test Data Input**

Serial input for boundary scan testing and diagnostic probe. In Flexible mode, TDI is active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TDO, I/O **Test Data Output**

Serial output for boundary scan testing. In flexible mode, TDO is active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state. When Silicon Explorer II is being used, TDO will act as an output when the checksum command is run. It will return to user /IO when checksum is complete.

TMS **Test Mode Select**

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO, TRST). In flexible mode when the TMS pin is set Low, the TCK, TDI, and TDO pins are boundary scan pins (refer to Table 1-6 on page 1-9). Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the logic reset state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The logic reset state is reached five TCK cycles after the TMS pin is set High. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications.

TRST, I/O **Boundary Scan Reset Pin**

Once it is configured as the JTAG Reset pin, the TRST pin functions as an active low input to asynchronously initialize or reset the boundary scan circuit. The TRST pin is equipped with an internal pull-up resistor. This pin functions as an I/O when the **Reserve JTAG Reset Pin** is not selected in Designer.

V_{CCI} **Supply Voltage**

Supply voltage for I/Os. See Table 2-2 on page 2-1. All V_{CCI} power pins in the device should be connected.

V_{CCA} **Supply Voltage**

Supply voltage for array. See Table 2-2 on page 2-1. All V_{CCA} power pins in the device should be connected.

Theta-JA

Junction-to-ambient thermal resistance (θ_{JA}) is determined under standard conditions specified by JESD-51 series but has little relevance in actual performance of the product in real application. It should be employed with caution but is useful for comparing the thermal performance of one package to another.

A sample calculation to estimate the absolute maximum power dissipation allowed (worst case) for a 329-pin PBGA package at still air is as follows. i.e.:

θ_{JA} = 17.1°C/W is taken from Table 2-12 on page 2-11

T_A = 125°C is the maximum limit of ambient (from the datasheet)

$$\text{Max. Allowed Power} = \frac{\text{Max Junction Temp} - \text{Max. Ambient Temp}}{\theta_{JA}} = \frac{150°C - 125°C}{17.1°C/W} = 1.46\ W$$

EQ 2-11

The device's power consumption must be lower than the calculated maximum power dissipation by the package.

The power consumption of a device can be calculated using the Actel power calculator. If the power consumption is higher than the device's maximum allowable power dissipation, then a heat sink can be attached on top of the case or the airflow inside the system must be increased.

Theta-JC

Junction-to-case thermal resistance (θ_{JC}) measures the ability of a device to dissipate heat from the surface of the chip to the top or bottom surface of the package. It is applicable for packages used with external heat sinks and only applies to situations where all or nearly all of the heat is dissipated through the surface in consideration. If the power consumption is higher than the calculated maximum power dissipation of the package, then a heat sink is required.

Calculation for Heat Sink

For example, in a design implemented in a FG484 package, the power consumption value using the power calculator is 3.00 W. The user-dependent data T_J and T_A are given as follows:

T_J = 110°C

T_A = 70°C

From the datasheet:

θ_{JA} = 18.0°C/W

θ_{JC} = 3.2 °C/W

$$P = \frac{\text{Max Junction Temp} - \text{Max. Ambient Temp}}{\theta_{JA}} = \frac{110°C - 70°C}{18.0°C/W} = 2.22\ W$$

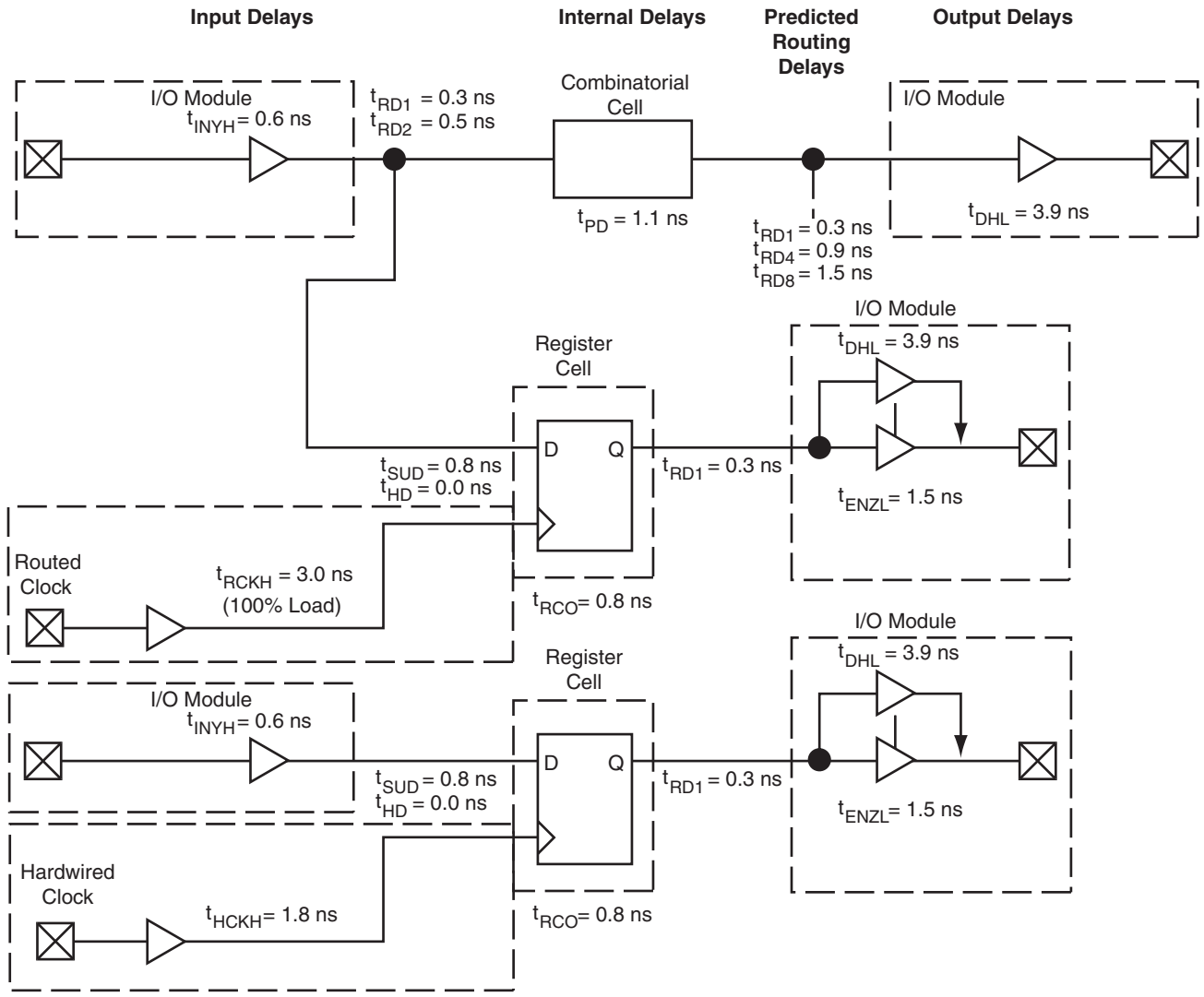
EQ 2-12

The 2.22 W power is less than then required 3.00 W; therefore, the design requires a heat sink or the airflow where the device is mounted should be increased. The design's junction-to-air thermal resistance requirement can be estimated by:

$$\theta_{JA} = \frac{\text{Max Junction Temp} - \text{Max. Ambient Temp}}{P} = \frac{110°C - 70°C}{3.00\ W} = 13.33°C/W$$

EQ 2-13

SX-A Timing Model



Note: **Values shown for A54SX72A, –2, worst-case commercial conditions at 5 V PCI with standard place-and-route.*

Figure 2-3 • **SX-A Timing Model**

Sample Path Calculations

Hardwired Clock

External Setup = $(t_{INYH} + t_{RD1} + t_{SUD}) - t_{HCKH}$
= 0.6 + 0.3 + 0.8 - 1.8 = – 0.1 ns

Clock-to-Out (Pad-to-Pad) = $t_{HCKH} + t_{RCO} + t_{RD1} + t_{DHL}$
= 1.8 + 0.8 + 0.3 + 3.9 = 6.8 ns

Routed Clock

External Setup = $(t_{INYH} + t_{RD1} + t_{SUD}) - t_{RCKH}$
= 0.6 + 0.3 + 0.8 - 3.0 = –1.3 ns

Clock-to-Out (Pad-to-Pad) = $t_{RCKH} + t_{RCO} + t_{RD1} + t_{DHL}$
= 3.0 + 0.8 + 0.3 + 3.9 = 8.0 ns

Timing Characteristics

Table 2-14 • **A54SX08A Timing Characteristics (Worst-Case Commercial Conditions, V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)**

Parameter	Description	–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays[1]										
t_{PD}	Internal Array Module		0.9		1.1		1.2		1.7	ns
Predicted Routing Delays[2]										
t_{DC}	FO = 1 Routing Delay, Direct Connect		0.1		0.1		0.1		0.1	ns
t_{FC}	FO = 1 Routing Delay, Fast Connect		0.3		0.3		0.4		0.6	ns
t_{RD1}	FO = 1 Routing Delay		0.3		0.4		0.5		0.6	ns
t_{RD2}	FO = 2 Routing Delay		0.5		0.5		0.6		0.8	ns
t_{RD3}	FO = 3 Routing Delay		0.6		0.7		0.8		1.1	ns
t_{RD4}	FO = 4 Routing Delay		0.8		0.9		1		1.4	ns
t_{RD8}	FO = 8 Routing Delay		1.4		1.5		1.8		2.5	ns
t_{RD12}	FO = 12 Routing Delay		2		2.2		2.6		3.6	ns
R-Cell Timing										
t_{RCO}	Sequential Clock-to-Q		0.7		0.8		0.9		1.3	ns
t_{CLR}	Asynchronous Clear-to-Q		0.6		0.6		0.8		1.0	ns
t_{PRESET}	Asynchronous Preset-to-Q		0.7		0.7		0.9		1.2	ns
t_{SUD}	Flip-Flop Data Input Set-Up	0.7		0.8		0.9		1.2		ns
t_{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		ns
t_{WASYN}	Asynchronous Pulse Width	1.4		1.5		1.8		2.5		ns
$t_{RECASYN}$	Asynchronous Recovery Time	0.4		0.4		0.5		0.7		ns
t_{HASYN}	Asynchronous Hold Time	0.3		0.3		0.4		0.6		ns
t_{MPW}	Clock Pulse Width	1.6		1.8		2.1		2.9		ns
Input Module Propagation Delays										
t_{INYH}	Input Data Pad to Y High 2.5 V LVCMOS		0.8		0.9		1.0		1.4	ns
t_{INYL}	Input Data Pad to Y Low 2.5 V LVCMOS		1.0		1.2		1.4		1.9	ns
t_{INYH}	Input Data Pad to Y High 3.3 V PCI		0.6		0.6		0.7		1.0	ns
t_{INYL}	Input Data Pad to Y Low 3.3 V PCI		0.7		0.8		0.9		1.3	ns
t_{INYH}	Input Data Pad to Y High 3.3 V LVTTL		0.7		0.7		0.9		1.2	ns
t_{INYL}	Input Data Pad to Y Low 3.3 V LVTTL		1.0		1.1		1.3		1.8	ns

Notes:

1. *For dual-module macros, use t_{PD} + t_{RD1} + t_{PDn} , t_{RCO} + t_{RD1} + t_{PDn} , or t_{PD1} + t_{RD1} + t_{SUD} , whichever is appropriate.*
2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.*

Table 2-21 • **A54SX16A Timing Characteristics (Continued)**
(Worst-Case Commercial Conditions, V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{INYH}	Input Data Pad to Y High 5 V PCI		0.5		0.5		0.6		0.7		0.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V PCI		0.7		0.8		0.9		1.1		1.5	ns
t_{INYH}	Input Data Pad to Y High 5 V TTL		0.5		0.5		0.6		0.7		0.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V TTL		0.7		0.8		0.9		1.1		1.5	ns
Input Module Predicted Routing Delays[2]												
t_{IRD1}	FO = 1 Routing Delay		0.3		0.3		0.3		0.4		0.6	ns
t_{IRD2}	FO = 2 Routing Delay		0.4		0.5		0.5		0.6		0.8	ns
t_{IRD3}	FO = 3 Routing Delay		0.5		0.6		0.7		0.8		1.1	ns
t_{IRD4}	FO = 4 Routing Delay		0.7		0.8		0.9		1.0		1.4	ns
t_{IRD8}	FO = 8 Routing Delay		1.2		1.4		1.5		0.8		2.5	ns
t_{IRD12}	FO = 12 Routing Delay		1.7		2.0		2.2		2.6		3.6	ns

Notes:

1. *All –3 speed grades have been discontinued.*
2. *For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.*
3. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.*

Table 2-27 • **A54SX16A Timing Characteristics (Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 4.75 V, T_J = 70°C)**

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
5 V PCI Output Module Timing[2]												
t_{DLH}	Data-to-Pad Low to High		2.2		2.5		2.8		3.3		4.6	ns
t_{DHL}	Data-to-Pad High to Low		2.8		3.2		3.6		4.2		5.9	ns
t_{ENZL}	Enable-to-Pad, Z to L		1.3		1.5		1.7		2.0		2.8	ns
t_{ENZH}	Enable-to-Pad, Z to H		2.2		2.5		2.8		3.3		4.6	ns
t_{ENLZ}	Enable-to-Pad, L to Z		3.0		3.5		3.9		4.6		6.4	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.8		3.2		3.6		4.2		5.9	ns
d_{TLH}[3]	Delta Low to High		0.016		0.016		0.02		0.022		0.032	ns/pF
d_{THL}[3]	Delta High to Low		0.026		0.03		0.032		0.04		0.052	ns/pF
5 V TTL Output Module Timing[4]												
t_{DLH}	Data-to-Pad Low to High		2.2		2.5		2.8		3.3		4.6	ns
t_{DHL}	Data-to-Pad High to Low		2.8		3.2		3.6		4.2		5.9	ns
t_{DHLS}	Data-to-Pad High to Low—low slew		6.7		7.7		8.7		10.2		14.3	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.1		2.4		2.7		3.2		4.5	ns
t_{ENZLS}	Enable-to-Pad, Z to L—low slew		7.4		8.4		9.5		11.0		15.4	ns
t_{ENZH}	Enable-to-Pad, Z to H		1.9		2.2		2.5		2.9		4.1	ns
t_{ENLZ}	Enable-to-Pad, L to Z		3.6		4.2		4.7		5.6		7.8	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.5		2.9		3.3		3.9		5.4	ns
d_{TLH}[3]	Delta Low to High		0.014		0.017		0.017		0.023		0.031	ns/pF
d_{THL}[3]	Delta High to Low		0.023		0.029		0.031		0.037		0.051	ns/pF
d_{THLS}[3]	Delta High to Low—low slew		0.043		0.046		0.057		0.066		0.089	ns/pF

Notes:

1. *All –3 speed grades have been discontinued.*
2. *Delays based on 50 pF loading.*
3. *To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:*
   Slew Rate [V/ns] = $(0.1*V_{CCI} – 0.9*V_{CCI})/ (C_{load} * d_{T[LH|HL|HLS]})$
   where C_{load} is the load capacitance driven by the I/O in pF
   $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. *Delays based on 35 pF loading.*

Table 2-30 • **A54SX32A Timing Characteristics (Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)**

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks												
t_{HCKH}	Input Low to High (Pad to R-cell Input)		1.7		2.0		2.2		2.6		4.0	ns
t_{HCKL}	Input High to Low (Pad to R-cell Input)		1.7		2.0		2.2		2.6		4.0	ns
t_{HPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t_{HPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t_{HCKSW}	Maximum Skew		0.6		0.6		0.7		0.8		1.3	ns
t_{HP}	Minimum Period	2.8		3.2		3.6		4.2		5.8		ns
f_{HMAX}	Maximum Frequency		357		313		278		238		172	MHz
Routed Array Clock Networks												
t_{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		2.2		2.5		2.8		3.3		4.6	ns
t_{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		2.1		2.4		2.7		3.2		4.5	ns
t_{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.3		2.7		3.1		3.6		5	ns
t_{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		2.2		2.5		2.9		3.4		4.7	ns
t_{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		2.4		2.8		3.2		3.7		5.2	ns
t_{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		2.4		2.8		3.1		3.7		5.1	ns
t_{RPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t_{RPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t_{RCKSW}	Maximum Skew (Light Load)		1.0		1.1		1.3		1.5		2.1	ns
t_{RCKSW}	Maximum Skew (50% Load)		0.9		1.0		1.2		1.4		1.9	ns
t_{RCKSW}	Maximum Skew (100% Load)		0.9		1.0		1.2		1.4		1.9	ns

Note: **All –3 speed grades have been discontinued.*

Table 2-35 • **A54SX72A Timing Characteristics (Worst-Case Commercial Conditions, V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)**

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays[2]												
t_{PD}	Internal Array Module		1.0		1.1		1.3		1.5		2.0	ns
Predicted Routing Delays[3]												
t_{DC}	FO = 1 Routing Delay, Direct Connect		0.1		0.1		0.1		0.1		0.1	ns
t_{FC}	FO = 1 Routing Delay, Fast Connect		0.3		0.3		0.3		0.4		0.6	ns
t_{RD1}	FO = 1 Routing Delay		0.3		0.3		0.4		0.5		0.7	ns
t_{RD2}	FO = 2 Routing Delay		0.4		0.5		0.6		0.7		1	ns
t_{RD3}	FO = 3 Routing Delay		0.5		0.7		0.8		0.9		1.3	ns
t_{RD4}	FO = 4 Routing Delay		0.7		0.9		1		1.1		1.5	ns
t_{RD8}	FO = 8 Routing Delay		1.2		1.5		1.7		2.1		2.9	ns
t_{RD12}	FO = 12 Routing Delay		1.7		2.2		2.5		3		4.2	ns
R-Cell Timing												
t_{RCO}	Sequential Clock-to-Q		0.7		0.8		0.9		1.1		1.5	ns
t_{CLR}	Asynchronous Clear-to-Q		0.6		0.7		0.7		0.9		1.2	ns
t_{PRESET}	Asynchronous Preset-to-Q		0.7		0.8		0.8		1.0		1.4	ns
t_{SUD}	Flip-Flop Data Input Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t_{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WASYN}	Asynchronous Pulse Width	1.3		1.5		1.7		2.0		2.8		ns
$t_{RECASYN}$	Asynchronous Recovery Time	0.3		0.4		0.4		0.5		0.7		ns
t_{HASYN}	Asynchronous Hold Time	0.3		0.3		0.3		0.4		0.6		ns
t_{MPW}	Clock Minimum Pulse Width	1.5		1.7		2.0		2.3		3.2		ns
Input Module Propagation Delays												
t_{INYH}	Input Data Pad to Y High 2.5 V LVCMOS		0.6		0.7		0.8		0.9		1.3	ns
t_{INYL}	Input Data Pad to Y Low 2.5 V LVCMOS		0.8		1.0		1.1		1.3		1.7	ns
t_{INYH}	Input Data Pad to Y High 3.3 V PCI		0.6		0.7		0.7		0.9		1.2	ns
t_{INYL}	Input Data Pad to Y Low 3.3 V PCI		0.7		0.8		0.9		1.0		1.4	ns
t_{INYH}	Input Data Pad to Y High 3.3 V LVTTL		0.7		0.7		0.8		1.0		1.4	ns
t_{INYL}	Input Data Pad to Y Low 3.3 V LVTTL		1.0		1.2		1.3		1.5		2.1	ns

Notes:

1. *All –3 speed grades have been discontinued.*
2. *For dual-module macros, use t_{PD} + t_{RD1} + t_{PDn} , t_{RCO} + t_{RD1} + t_{PDn} , or t_{PD1} + t_{RD1} + t_{SUD} , whichever is appropriate.*
3. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.*

Table 2-35 • **A54SX72A Timing Characteristics (Continued)**
(Worst-Case Commercial Conditions, V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{INYH}	Input Data Pad to Y High 5 V PCI		0.5		0.6		0.7		0.8		1.1	ns
t_{INYL}	Input Data Pad to Y Low 5 V PCI		0.8		0.9		1.0		1.2		1.6	ns
t_{INYH}	Input Data Pad to Y High 5 V TTL		0.7		0.8		0.9		1.0		1.4	ns
t_{INYL}	Input Data Pad to Y Low 5 V TTL		0.9		1.1		1.2		1.4		1.9	ns
Input Module Predicted Routing Delays[3]												
t_{IRD1}	FO = 1 Routing Delay		0.3		0.3		0.4		0.5		0.7	ns
t_{IRD2}	FO = 2 Routing Delay		0.4		0.5		0.6		0.7		1	ns
t_{IRD3}	FO = 3 Routing Delay		0.5		0.7		0.8		0.9		1.3	ns
t_{IRD4}	FO = 4 Routing Delay		0.7		0.9		1		1.1		1.5	ns
t_{IRD8}	FO = 8 Routing Delay		1.2		1.5		1.7		2.1		2.9	ns
t_{IRD12}	FO = 12 Routing Delay		1.7		2.2		2.5		3		4.2	ns

Notes:

1. *All –3 speed grades have been discontinued.*
2. *For dual-module macros, use t_{PD} + t_{RD1} + t_{PDn} , t_{RCO} + t_{RD1} + t_{PDn} , or t_{PD1} + t_{RD1} + t_{SUD} , whichever is appropriate.*
3. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.*

Table 2-40 • **A54SX72A Timing Characteristics (Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)**

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
3.3 V PCI Output Module Timing[2]												
t_{DLH}	Data-to-Pad Low to High		2.3		2.7		3.0		3.6		5.0	ns
t_{DHL}	Data-to-Pad High to Low		2.5		2.9		3.2		3.8		5.3	ns
t_{ENZL}	Enable-to-Pad, Z to L		1.4		1.7		1.9		2.2		3.1	ns
t_{ENZH}	Enable-to-Pad, Z to H		2.3		2.7		3.0		3.6		5.0	ns
t_{ENLZ}	Enable-to-Pad, L to Z		2.5		2.8		3.2		3.8		5.3	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.5		2.9		3.2		3.8		5.3	ns
d_{TLH}[3]	Delta Low to High		0.025		0.03		0.03		0.04		0.045	ns/pF
d_{THL}[3]	Delta High to Low		0.015		0.015		0.015		0.015		0.025	ns/pF
3.3 V LVTTL Output Module Timing[4]												
t_{DLH}	Data-to-Pad Low to High		3.2		3.7		4.2		5.0		6.9	ns
t_{DHL}	Data-to-Pad High to Low		3.2		3.7		4.2		4.9		6.9	ns
t_{DHLS}	Data-to-Pad High to Low—low slew		10.3		11.9		13.5		15.8		22.2	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.2		2.6		2.9		3.4		4.8	ns
t_{ENZLS}	Enable-to-Pad, Z to L—low slew		15.8		18.9		21.3		25.4		34.9	ns
t_{ENZH}	Enable-to-Pad, Z to H		3.2		3.7		4.2		5.0		6.9	ns
t_{ENLZ}	Enable-to-Pad, L to Z		2.9		3.3		3.7		4.4		6.2	ns
t_{ENHZ}	Enable-to-Pad, H to Z		3.2		3.7		4.2		4.9		6.9	ns
d_{TLH}[3]	Delta Low to High		0.025		0.03		0.03		0.04		0.045	ns/pF
d_{THL}[3]	Delta High to Low		0.015		0.015		0.015		0.015		0.025	ns/pF
d_{THLS}[3]	Delta High to Low—low slew		0.053		0.053		0.067		0.073		0.107	ns/pF

Notes:

1. *All –3 speed grades have been discontinued.*
2. *Delays based on 10 pF loading and 25 Ω resistance.*
3. *To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:*
   Slew Rate [V/ns] = $(0.1*V_{CCI} – 0.9*V_{CCI})/ (C_{load} * d_{T[LH|HL|HLS]})$
   where C_{load} is the load capacitance driven by the I/O in pF
   $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. *Delays based on 35 pF loading.*

100-TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	TMS	TMS	TMS
8	V_{CCI}	V_{CCI}	V_{CCI}
9	GND	GND	GND
10	I/O	I/O	I/O
11	I/O	I/O	I/O
12	I/O	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	TRST, I/O	TRST, I/O	TRST, I/O
17	I/O	I/O	I/O
18	I/O	I/O	I/O
19	I/O	I/O	I/O
20	V_{CCI}	V_{CCI}	V_{CCI}
21	I/O	I/O	I/O
22	I/O	I/O	I/O
23	I/O	I/O	I/O
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	I/O	I/O	I/O
29	I/O	I/O	I/O
30	I/O	I/O	I/O
31	I/O	I/O	I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	PRB, I/O	PRB, I/O	PRB, I/O
35	V_{CCA}	V_{CCA}	V_{CCA}

100-TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
36	GND	GND	GND
37	NC	NC	NC
38	I/O	I/O	I/O
39	HCLK	HCLK	HCLK
40	I/O	I/O	I/O
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	V_{CCI}	V_{CCI}	V_{CCI}
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	TDO, I/O	TDO, I/O	TDO, I/O
50	I/O	I/O	I/O
51	GND	GND	GND
52	I/O	I/O	I/O
53	I/O	I/O	I/O
54	I/O	I/O	I/O
55	I/O	I/O	I/O
56	I/O	I/O	I/O
57	V_{CCA}	V_{CCA}	V_{CCA}
58	V_{CCI}	V_{CCI}	V_{CCI}
59	I/O	I/O	I/O
60	I/O	I/O	I/O
61	I/O	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	I/O	I/O	I/O
65	I/O	I/O	I/O
66	I/O	I/O	I/O
67	V_{CCA}	V_{CCA}	V_{CCA}
68	GND	GND	GND
69	GND	GND	GND
70	I/O	I/O	I/O

256-Pin FBGA			
Pin Number	**A54SX16A Function**	**A54SX32A Function**	**A54SX72A Function**
P15	I/O	I/O	I/O
P16	I/O	I/O	I/O
R1	I/O	I/O	I/O
R2	GND	GND	GND
R3	I/O	I/O	I/O
R4	NC	I/O	I/O
R5	I/O	I/O	I/O
R6	I/O	I/O	I/O
R7	I/O	I/O	I/O
R8	I/O	I/O	I/O
R9	HCLK	HCLK	HCLK
R10	I/O	I/O	QCLKB
R11	I/O	I/O	I/O
R12	I/O	I/O	I/O
R13	I/O	I/O	I/O
R14	I/O	I/O	I/O
R15	GND	GND	GND
R16	GND	GND	GND
T1	GND	GND	GND
T2	I/O	I/O	I/O
T3	I/O	I/O	I/O
T4	NC	I/O	I/O
T5	I/O	I/O	I/O
T6	I/O	I/O	I/O
T7	I/O	I/O	I/O
T8	I/O	I/O	I/O
T9	V_{CCA}	V_{CCA}	V_{CCA}
T10	I/O	I/O	I/O
T11	I/O	I/O	I/O
T12	NC	I/O	I/O
T13	I/O	I/O	I/O
T14	I/O	I/O	I/O
T15	TDO, I/O	TDO, I/O	TDO, I/O
T16	GND	GND	GND

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
K10	GND	GND
K11	GND	GND
K12	GND	GND
K13	GND	GND
K14	GND	GND
K15	GND	GND
K16	GND	GND
K17	GND	GND
K22	I/O	I/O
K23	I/O	I/O
K24	NC*	NC
K25	NC*	I/O
K26	NC*	I/O
L1	NC*	I/O
L2	NC*	I/O
L3	I/O	I/O
L4	I/O	I/O
L5	I/O	I/O
L10	GND	GND
L11	GND	GND
L12	GND	GND
L13	GND	GND
L14	GND	GND
L15	GND	GND
L16	GND	GND
L17	GND	GND
L22	I/O	I/O
L23	I/O	I/O
L24	I/O	I/O
L25	I/O	I/O
L26	I/O	I/O
M1	NC*	NC
M2	I/O	I/O
M3	I/O	I/O
M4	I/O	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
M5	I/O	I/O
M10	GND	GND
M11	GND	GND
M12	GND	GND
M13	GND	GND
M14	GND	GND
M15	GND	GND
M16	GND	GND
M17	GND	GND
M22	I/O	I/O
M23	I/O	I/O
M24	I/O	I/O
M25	NC*	I/O
M26	NC*	I/O
N1	I/O	I/O
N2	V_{CCI}	V_{CCI}
N3	I/O	I/O
N4	I/O	I/O
N5	I/O	I/O
N10	GND	GND
N11	GND	GND
N12	GND	GND
N13	GND	GND
N14	GND	GND
N15	GND	GND
N16	GND	GND
N17	GND	GND
N22	V_{CCA}	V_{CCA}
N23	I/O	I/O
N24	I/O	I/O
N25	I/O	I/O
N26	NC*	NC
P1	NC*	I/O
P2	NC*	I/O
P3	I/O	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
P4	I/O	I/O
P5	V_{CCA}	V_{CCA}
P10	GND	GND
P11	GND	GND
P12	GND	GND
P13	GND	GND
P14	GND	GND
P15	GND	GND
P16	GND	GND
P17	GND	GND
P22	I/O	I/O
P23	I/O	I/O
P24	V_{CCI}	V_{CCI}
P25	I/O	I/O
P26	I/O	I/O
R1	NC*	I/O
R2	NC*	I/O
R3	I/O	I/O
R4	I/O	I/O
R5	TRST, I/O	TRST, I/O
R10	GND	GND
R11	GND	GND
R12	GND	GND
R13	GND	GND
R14	GND	GND
R15	GND	GND
R16	GND	GND
R17	GND	GND
R22	I/O	I/O
R23	I/O	I/O
R24	I/O	I/O
R25	NC*	I/O
R26	NC*	I/O
T1	NC*	I/O
T2	NC*	I/O

Note: **These pins must be left floating on the A54SX32A device.*

484-Pin FBGA		
Pin Number	**A54SX32A Function**	**A54SX72A Function**
T3	I/O	I/O
T4	I/O	I/O
T5	I/O	I/O
T10	GND	GND
T11	GND	GND
T12	GND	GND
T13	GND	GND
T14	GND	GND
T15	GND	GND
T16	GND	GND
T17	GND	GND
T22	I/O	I/O
T23	I/O	I/O
T24	I/O	I/O
T25	NC*	I/O
T26	NC*	I/O
U1	I/O	I/O
U2	V_{CCI}	V_{CCI}
U3	I/O	I/O
U4	I/O	I/O
U5	I/O	I/O
U10	GND	GND
U11	GND	GND
U12	GND	GND
U13	GND	GND
U14	GND	GND
U15	GND	GND
U16	GND	GND
U17	GND	GND
U22	I/O	I/O
U23	I/O	I/O
U24	I/O	I/O
U25	V_{CCI}	V_{CCI}
U26	I/O	I/O
V1	NC*	I/O

484-Pin FBGA		
Pin Number	**A54SX32A Function**	**A54SX72A Function**
V2	NC*	I/O
V3	I/O	I/O
V4	I/O	I/O
V5	I/O	I/O
V22	V_{CCA}	V_{CCA}
V23	I/O	I/O
V24	I/O	I/O
V25	NC*	I/O
V26	NC*	I/O
W1	I/O	I/O
W2	I/O	I/O
W3	I/O	I/O
W4	I/O	I/O
W5	I/O	I/O
W22	I/O	I/O
W23	V_{CCA}	V_{CCA}
W24	I/O	I/O
W25	NC*	I/O
W26	NC*	I/O
Y1	NC*	I/O
Y2	NC*	I/O
Y3	I/O	I/O
Y4	I/O	I/O
Y5	NC*	I/O
Y22	I/O	I/O
Y23	I/O	I/O
Y24	V_{CCI}	V_{CCI}
Y25	I/O	I/O
Y26	I/O	I/O

Note: **These pins must be left floating on the A54SX32A device.*

Previous Version	Changes in Current Version (v5.3)	Page
v4.0 (continued)	Table 2-12 was updated.	2-11
	The was updated.	2-14
	The "Sample Path Calculations" were updated.	2-14
	Table 2-13 was updated.	2-17
	Table 2-13 was updated.	2-17
	All timing tables were updated.	2-18 to 2-52
v3.0	The "Actel Secure Programming Technology with FuseLock™ Prevents Reverse Engineering and Design Theft" section was updated.	1-i
	The "Ordering Information" section was updated.	1-ii
	The "Temperature Grade Offering" section was updated.	1-iii
	The Figure 1-1 • SX-A Family Interconnect Elements was updated.	1-1
	The ""Clock Resources" section"was updated	1-5
	The Table 1-1 • SX-A Clock Resources is new.	1-5
	The "User Security" section is new.	1-7
	The "I/O Modules" section was updated.	1-7
	The Table 1-2 • I/O Features was updated.	1-8
	The Table 1-3 • I/O Characteristics for All I/O Configurations is new.	1-8
	The Table 1-4 • Power-Up Time at which I/Os Become Active is new	1-8
	The Figure 1-12 • Device Selection Wizard is new.	1-9
	The "Boundary-Scan Pin Configurations and Functions" section is new.	1-9
	The Table 1-9 • Device Configuration Options for Probe Capability (TRST Pin Reserved) is new.	1-11
	The "SX-A Probe Circuit Control Pins" section was updated.	1-12
	The "Design Considerations" section was updated.	1-12
	The Figure 1-13 • Probe Setup was updated.	1-12
	The Design Environment was updated.	1-13
	The Figure 1-13 • Design Flow is new.	1-11
	The "Absolute Maximum Ratings*" section was updated.	1-12
	The "Recommended Operating Conditions" section was updated.	1-12
	The "Electrical Specifications" section was updated.	1-12
	The "2.5V LVCMOS2 Electrical Specifications" section was updated.	1-13
	The "SX-A Timing Model" and "Sample Path Calculations" equations were updated.	1-23
	The "Pin Description" section was updated.	1-15
v2.0.1	The "Design Environment" section has been updated.	1-13
	The "I/O Modules" section, and Table 1-2 • I/O Features have been updated.	1-8
	The "SX-A Timing Model" section and the "Timing Characteristics" section have new timing numbers.	1-23